

Form PTO-1449

Equivalent

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DKT. NO.

500.43701X00

SERIAL NO.

10/809,464

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

(Use several sheets if necessary)

APPLICANT

OKUDA et al

FILING DATE

March 26, 2004

GROUP

2621

U.S. PATENT DOCUMENTS

Ex. Initial	Doc. No.	Date	Name	Class	Subclass	Filing Date
/E.P./	AA	5,699,447	12/97	Alumot et al		
	AB					
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U.S. PATENT APPLICATIONS

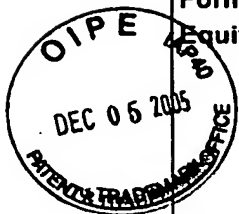
	Publication Number	Name	Publication Date
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FOREIGN PATENT DOCUMENTS

	Doc. No.	Date	Country	Class	Subclass	Translation/Abstract?	
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AM							
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OTHER DOCUMENTS

AR	
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Examiner	
/Edward Park/	
Date Considered	
07/07/2007	



Form PTO-1449 Equivalent	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTY. DKT. NO. 500.43701X00	SERIAL NO. 10/809,464
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	Doc. No.	Date	Country	Class	Subclass	Translation/Abstract?	
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/E.P./	AR	Kuk Wo Ko, Such Cho, "Solder Joints Inspection Using A Neural Network and Fuzzy Rule-Based Classification Method", IEEE Transactions On Electronics Packaging Manufacturing, vol. 23, no. 2, April 2000 pp 93-103
/E.P./	AS	Xu, L, "Methods of Combining Multiple Classifiers And Their Applications To Handwriting Recognition" IEEE Transactions on Systems, Man and Cybernetics, vol. 22 no. 3 May 1992, pp 418-435
/E.P./	AT	Henry, et al "Application of ADC Techniques to Characterize Yield-Limiting Defects Identified With the Overlay of E-Test/Inspecting Data On Short Loop Process Testers" Advanced Semiconductor Manufacturing Conference, 1999 IEEE/SEMI Boston, MA 8-10 Sept. 1999 pp 330-337
Examiner /Edward Park/		
Date Considered 07/07/2007		



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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(file as many sheets as necessary)</i>		Complete if Known			
		Application Number	10/809,464		
		Filing Date	3/26/2004		
		First Named Inventor	OKUDA et al		
		Art Unit	2621		
Sheet	1	of	1	Examiner Name	
				Attorney Docket Number	500.43701X00

U.S. PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Document Number		Patent Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)				
/E.P./		US- 6,922,482		7/26/05	Ben-Porath	
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FOREIGN PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
/E.P./		JP 2001-135692	5/18/01	Applied Materials, Inc.	English Translation	

Examiner Signature	/Edward Park/	Date Considered	07/07/2007
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Substitute for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>			Complete If Known		
			Application Number	Not Yet Assigned	
			Filing Date	March 26, 2004	
			First Named Inventor	Hirohito OKUDA	
			Art Unit		
			Examiner Name		
Sheet	1	of	1	Attorney Docket Number	500.43701X00

U.S. PATENT DOCUMENTS						
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		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)					
/E.P./		JP A-2001-135692		May 18, 2001	A. BEN-PORETH		X

Examiner Signature	/Edward Park/	Date Considered	07/07/2007
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